

FDD6696/FDU6696

30V N-Channel PowerTrench^O MOSFET

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low RDS(ON) and fast switching speed.

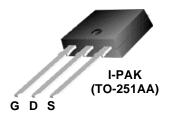
Applications

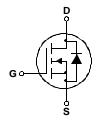
- DC/DC converter
- Motor drives

Features

- 50A, 30 V $R_{DS(ON)} = 8.0 \ m\Omega \ @ \ V_{GS} = 10 \ V$ $R_{DS(ON)} = 10.7 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$
- Low gate charge (17nC typical)
- Fast switching
- High performance trench technology for extremely low R_{DS(ON)}







Absolute Maximum Ratings T_A=25°C unless otherwise noted

| Symbol | Para | meter | | Ratings | Unit s |
|-----------------------------------|--|-----------------------|-----------|-------------|-----------|
| V_{DSS} | Drain-Source Voltage | | | 30 | V |
| V_{GSS} | Gate-Source Voltage | | | ± 16 | |
| I _D | Continuous Drain Current | @T _C =25°C | (Note 3) | 50 | Α |
| | | @T _A =25°C | (Note 1a) | 13 | |
| | | Pulsed | (Note 1a) | 100 | |
| P _D | Power Dissipation | @T _C =25°C | (Note 3) | 52 | W |
| | | @T _A =25°C | (Note 1a) | 3.8 | |
| | | @T _A =25°C | (Note 1b) | 1.6 | |
| T _J , T _{STG} | Operating and Storage Junction Temperature Range | | | -55 to +175 | °C |

Thermal Characteristics

| R _{0JC} | Thermal Resistance, Junction-to-Case | (Note 1) | 2.9 | °C/W |
|------------------|---|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | (Note 1a) | 40 | |
| | Thermal Resistance, Junction-to-Ambient | (Note 1b) | 96 | |

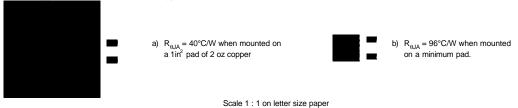
Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape width | Quantity |
|----------------|---------|----------------|-----------|------------|------------|
| FDD6696 | FDD6696 | D-PAK (TO-252) | 13" | 12mm | 2500 units |
| FDU6696 | FDU6696 | I-PAK (TO-251) | Tube | N/A | 75 |

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Unit s |
|--|---|--|-----|--------------------|---------------------|-----------|
| Drain-So | urce Avalanche Ratings (Note | e 2) | II. | ı | l | 1 |
| E _{AS} | Drain-Source Avalanche Energy | Single Pulse, V _{DD} = 15 V, I _D =13A | | | 165 | mJ |
| l _{AS} | Drain-Source Avalanche Current | | | | 13 | Α |
| Off Chara | acteristics | | • | | • | |
| BV _{DSS} | Drain–Source Breakdown Voltage | $V_{GS} = 0 \text{ V}, \qquad I_D = 250 \mu\text{A}$ | 30 | | | V |
| ΔBV DSS ΔTJ | Breakdown Voltage Temperature Coefficient | I_D = 250 μ A, Referenced to 25°C | | 23 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$ | | | 10 | μА |
| IGSSF | Gate-Body Leakage | $V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$ | | | ± 100 | nA |
| On Chara | acteristics (Note 2) | | • | I | 1 | I |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{CS}$, $I_D = 250 \mu A$ | 1 | 2 | 3 | V |
| $\Delta V_{GS(th)} \over \Delta T_{J}$ | Gate Threshold Voltage Temperature Coefficient | I_D = 250 μ A, Referenced to 25°C | | - 5 | | mV/°C |
| R _{DS(on)} | Static Drain–Source On–Resistance | $V_{GS} = 10 \text{ V}, \qquad I_D = 13 \text{ A} $ $V_{GS} = 4.5 \text{ V}, \qquad I_D = 12 \text{ A} $ $V_{GS} = 10 \text{ V}, \qquad I_D = 13 \text{ A}, \qquad T_J = 125 ^{\circ}\text{C}$ | | 6.7 8.6 10.2 | 8.0 10.7 15.0 | mΩ |
| g FS | Forward Transconductance | $V_{DS} = 5 \text{ V}, \qquad I_{D} = 13 \text{ A}$ | | 51 | | S |
| Dynamic | Characteristics | | | | | |
| C _{iss} | Input Capacitance | $V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ | | 1715 | | pF |
| Coss | Output Capacitance | f = 1.0 MHz | | 410 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 180 | | pF |
| R _G | Gate Resistance | $V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$ | | 1.3 | | Ω |
| Switching | g Characteristics (Note 2) | | | | • | |
| t _{d(on)} | Turn–On Delay Time | $V_{DD} = 15 \text{ V}, \qquad I_D = 13 \text{ A},$ | | 13 | 23 | ns |
| t _r | Turn-On Rise Time | $V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ | | 4 | 9 | ns |
| t _{d(off)} | Turn-Off Delay Time | | | 27 | 43 | ns |
| t _f | Turn-Off Fall Time | | | 17 | 31 | ns |
| Qg | Total Gate Charge | $V_{DS} = 15V$, $I_{D} = 13 \text{ A}$, | | 17 | 24 | nC |
| Q _{gs} | Gate-Source Charge | $V_{GS} = 5 V$ | | 5 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 6 | | nC |
| Drain-So | urce Diode Characteristics | and Maximum Ratings | | | | |
| ls | Maximum Continuous Drain-Sour | ce Diode Forward Current | | | 13 | Α |
| V _{SD} | Drain–Source Diode Forward Voltage | $V_{GS} = 0 \text{ V}, I_S = 13 \text{ A}$ (Note 2) | | 0.8 | 1.2 | V |
| t _{rr} | Diode Reverse Recovery Time | I _F = 13 A, | | 27 | | nS |
| Q _{rr} | Diode Reverse Recovery Charge | $d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$ | | 15 | | nC |

Notes:

 R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{8JC} is guaranteed by design while R_{9CA} is determined by the user's board design.



2. Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%

3. Maximum current is calculated as: current limitation is 21A

 $\sqrt{\frac{P_D}{R_{DS(ON)}}}$

where P_D is maximum power dissipation at T_C = 25°C and $R_{DS(on)}$ is at $T_{J(max)}$ and V_{GS} = 10V. Package

Typical Characteristics

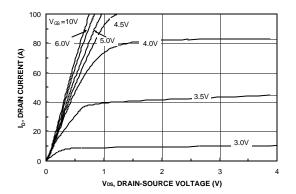


Figure 1. On-Region Characteristics

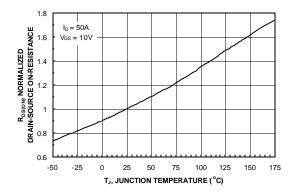


Figure 3. On-Resistance Variation with Temperature

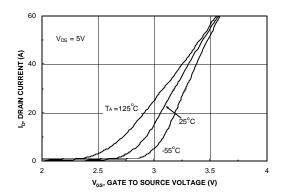


Figure 5. Transfer Characteristics

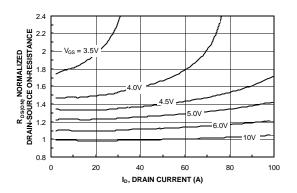


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

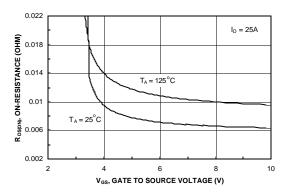


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

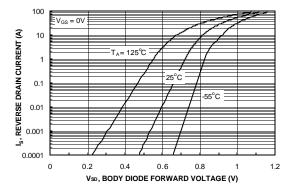
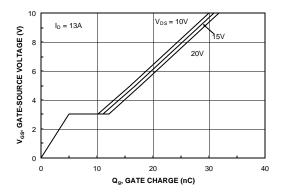


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

Typical Characteristics



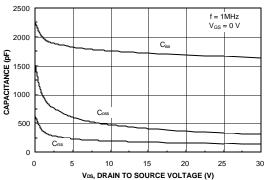
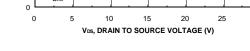
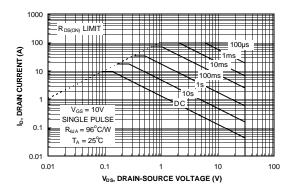
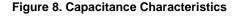


Figure 7. Gate Charge Characteristics







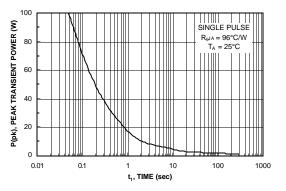


Figure 9. Maximum Safe Operating Area



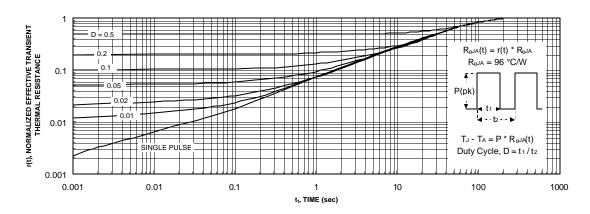


Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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